


<b>Search Notes</b>  	<b>Application/Control No.</b>  1082862812423894	<b>Applicant(s)/Patent Under Reexamination</b>  BUNDY ET AL.ZHANG ET AL.
	<b>Examiner</b>  John ChavisJohn Chavis	<b>Art Unit</b>  21932193

SEARCHED			
Class	Subclass	Date	Examiner
717717	149124-131	11/17/099/27/08	/JC//JC/
717	124	5/8/09	/JC/
717	124	12/12/09	/JC/

SEARCH NOTES		
Search Notes	Date	Examiner
West (IBM TDB, Derwent, EPO, JPO, USPAT, PGPUBS) anded with word searchWEST Search anded with word search	11/17/094/2/08	/JC//JC/
West Update anded with word search	5/8/09	/JC/
West Update anded with word search	12/12/09	/JC/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
717	149	11/17/09	/JC/

--	--